EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S59	20	(US-5825647-$ or US-6263299-$ or US-6978438-$ or US-7073162-$ or US-6226781-$ or US-6467076-$ or US-6649309-$ or US-6301697-$ or US-6430737-$ or US-6928634-$ or US-6813757-$ or US-6370679-$ or US-6312854-$ or US-6120952-$ or US-6080527-$ or US-6643616-$ or US-6033814-$ or US-6249904-$ or US-5815685-$ or US-6269472-$).did.	USPAT	OR	ON	2007/05/04 22:21
S60	1	S59 AND (control$1site (control adj site))	USPAT	OR	ON	2007/05/04 22:41
S61	26	("20040088149" | "4762396" | "5502654" | "5655110" | "5723233" | "5825647" | "5879844" | "6016357" | "6049660" | "6077310" | "6120952" | "6128067" | "6187483" | "6243855" | "6249904" | "6263299" | "6269472" | "6301697" | "6370679" | "6425117" | "6453452" | "6453457" | "6467076" | "6499003" | "6643616" | "6928634").PN. OR ("7073162").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/05/04 22:41
S62	0	S61 AND (control$1site (control adj site))	USPAT	OR	ON	2007/05/06 17:27
S63	20	(US-5825647-$ or US-6263299-$ or US-6978438-$ or US-7073162-$ or US-6226781-$ or US-6467076-$ or US-6649309-$ or US-6301697-$ or US-6430737-$ or US-6928634-$ or US-6813757-$ or US-6370679-$ or US-6312854-$ or US-6120952-$ or US-6080527-$ or US-6643616-$ or US-6033814-$ or US-6249904-$ or US-5815685-$ or US-6269472-$).did.	USPAT	OR	ON	2007/05/06 16:33
S64	3	S63 AND ((parallel co$1incident coincident) WITH (edge arc))	USPAT	OR	ON	2007/05/06 18:03
S65	6	S63 AND ((edge arc) WITH (curvature (intensity NEAR light)))	USPAT	OR	ON	2007/05/06 17:35
S66	2	S63 AND (control$1point (control adj point))	USPAT	OR	ON	2007/05/06 17:41
S67	33	("20020199157" | "20040005089" | "20040088149" | "4532650" | "4762396" | "5502654" | "5655110" | "5699447" | "5723233" | "5825647" | "5879844" | "6016357" | "6049660" | "6077310" | "6120952" | "6128067" | "6187483" | "6243855" | "6249904" | "6263299" | "6269472" | "6301697" | "6317859" | "6370679" | "6425117" | "6453452" | "6453457" | "6467076" | "6499003" | "6665845" | "6792159").PN. OR ("6928634").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/05/06 17:35
S68	4	S67 AND ((edge arc) WITH (curvature (intensity NEAR light)))	USPAT	OR	ON	2007/05/06 17:44
S69	1	S68 not S65	USPAT	OR	ON	2007/05/06 17:36
S70	5	S67 AND ((parallel co$1incident coincident) WITH (edge arc))	USPAT	OR	ON	2007/05/06 17:37
S71	1	S63 AND (dissection$1point di$1ssection$1point evaluation$1point (dissection adj point) (di$1ssection adj point) (evaluation adj point))	USPAT	OR	ON	2007/05/06 17:41
S72	66	("5124931" | "5206820" | "5656402").PN. OR ("5825647"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/05/06 17:44
S73	5	S72 AND ((edge arc) WITH (curvature (intensity NEAR light)))	USPAT	OR	ON	2007/05/06 17:59
S74	47	("5422491" | "5561317" | "5667923" | "5698346" | "5700601" | "5792581" | "5825647").PN. OR ("5991006").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/05/06 17:58
S75	5	S74 AND ((edge arc) WITH (curvature (intensity NEAR light)))	USPAT	OR	ON	2007/05/06 17:59
S76	18	(S72 S74) AND ((parallel co$1incident coincident) WITH (edge arc))	USPAT	OR	ON	2007/05/06 18:46
S77	0	(S63 S67 S72 S74) AND (tangent WITH (edge arc))	USPAT	OR	ON	2007/05/06 18:49
S78	0	(S63 S67 S72 S74) AND (intensity WITH slope WITH derivative)	USPAT	OR	ON	2007/05/06 19:47
S79	2	(S63 S67 S72 S74) AND (intensity WITH cutline)	USPAT	OR	ON	2007/05/06 19:47
S80	4	((("6973633") or ("7155699")).PN.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/05/06 20:22

| S81 | 15 | (("7178128") or ("6681379") or ("7169515") or ("6457168") or ("7181721") or ("7155699") or ("6301697") or ("6457168") or ("6523165")).PN. | US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2007/05/06 20:47 |

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